

TRANSISTOR MOS-FET IGBT DIODE

$\Delta V_{BE}/\Delta V_{DS}/\Delta V_{GE}/\Delta V_{CE}/\Delta V_F$ 過渡熱抵抗測定器

NEW

DVFN2050

2000V
50A

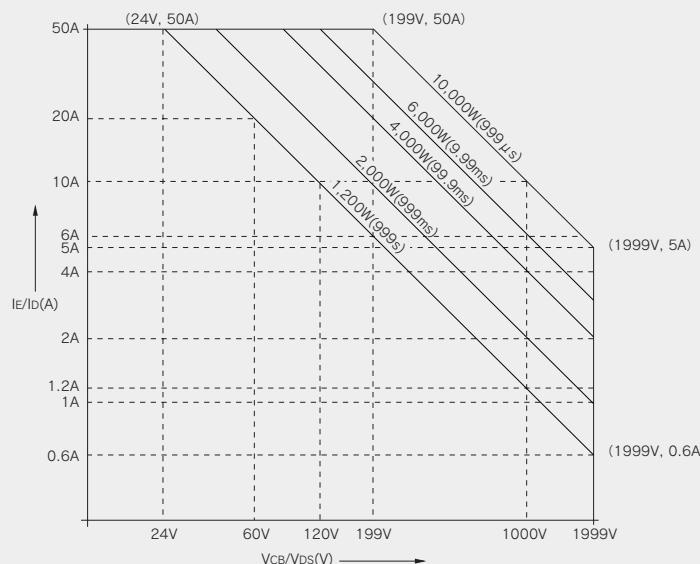
● DVFN2050 is thermal resistance test system with forcing voltage 2000V in maximum. It can force 999sec at 1200W line so it is adequate thermal evaluation for power device in high voltage.

● DVFN2050は最大印加電圧2000Vの性能を持つ熱抵抗測定器です。1200Wラインで999secの印加が可能でパワーデバイスの高電圧の熱的評価に最適です。



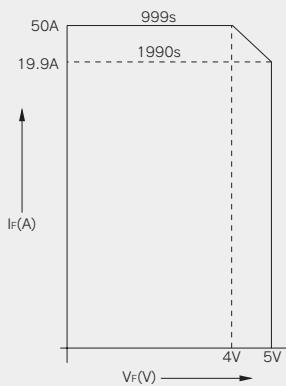
Forcing Power Range Diagram

[TRANSISTOR, IGBT, MOS-FET]

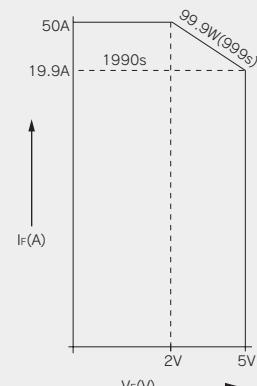


[DIODE]

IF CONSTANT



Power Constant Mode



MODEL

DVFN2050

MEASUREMENT RANGE

PRE-TEST	V _{BE1} /V _{DS1} /V _{F1} /V _{GE1} /V _{CE1}	0000mV~9999mV
	$\Delta V_{BE}/\Delta V_{DS}/\Delta V_F/\Delta V_{GE1}/\Delta V_{CE1}$	0000mV~1999mV

SETTING RANGE

MEASURABLE DEVICES	NPN/PNP, N/P-MOS FET, N/P-DIODE, N/P-IGBT(GE), N/P-IGBT(CE)
V _{CB} /V _{DS}	1V~1999V
I _E /I _D	1mA~50.0mA
DIODE FORCING POWER CONSTANT	1.00W~9.99W 10.0W~99.9W
I _M	0.1mA~99.9mA
POWER FORCING TIME(PT)	100μs~999s
DELAY TIME(DT)	10μs~999μs
GATE LIMIT(GL)	1.0V~19.9V
LOWER GATE(LG)/UPPER GATE(UG)	0000mV~1999mV
BINNING	
OPEN/SHORT CHECK	V _{F1} >4V---OPEN V _{F1} <0.2V---SHORT
BIN INDICATION	PASS, LOW, HIGH, AVAL, REJECT
DIMENSIONS & WEIGHT	550(W)×860+420(D)×1700(H)…400kg